

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/679,326	WEINL ET AL.		
Examiner	Art Unit		
John P. Sheehan	1742		

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
PG Pub	Search	8/2/2007	JPS	
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SEARCH N (INCLUDING SEARC		)
	DATE	EXMR
EAST	5/30/2006	JS
PALM Inventor Name Search	5/30/2006	JS
EAST Update	8/2/2007	JPS